

## Device Characterization Project #1

### PN DIODE CHARACTERIZATION

Please write your recitation time on your project report.

#### Introduction

The goal of the device characterization projects in 6.012 is to expose students to real microelectronics devices: current-voltage characteristics, parameter extraction techniques, and models. These projects use the MIT Microelectronics WebLab, an online microelectronics device characterization test station that Prof. del Alamo and his students have been developing for a while in his lab at MIT. The MIT Microelectronics WebLab is an experimental set up designed to allow the educational use of professional microelectronics characterization equipment by a large number of users through the internet.

Access to WebLab is provided through the MIT iLab Service Broker available at <http://ilab.mit.edu>. Your first step is to register by clicking on the "New user registration" button. Then select admission in the "6.012 students" group. Registration is not automatic but actually must be approved by the system manager. You should therefore register early. Your one-stop shopping location for help, of any kind, regarding this assignment is through the "Report a Bug" tab in the iLab website. A manual for the use of this system can be downloaded from this site after logging in.

Engineers working at the cutting edge often use state-of-the-art design and simulation tools in their work. This is worthwhile even if it means dealing with a few bugs, small annoyances, and less than optimal documentation. WebLab 6.0 and the MIT iLab Service Broker are the latest generation in online microelectronic device characterization. In spite of extensive testing, it is possible that a few bugs remain. As engineers working at the state-of-the-art, you should approach this project in a conservative way and carry out your assignment as early as possible. You should also seek help if you find any difficulties.

In the device characterization projects of 6.012, you will carry out a fairly detailed DC characterization of several microelectronic devices using an HP4155B Semiconductor Parameter Analyzer. This professional tool is basically a fancy curve tracer that allows

you to obtain current-voltage (I-V) characteristics of semiconductor devices. The first device to be characterized is a p-n junction diode.

In this assignment, you will carry out the device characterization before the relevant theoretical material is presented in lecture. This is due to scheduling constraints, although we hope it will give you a strong motivation to learn the theoretical material when it is discussed.

### **Assignment: pn diode characterization**

This problem is about characterizing a pn diode that is currently connected to the MIT Microelectronics WebLab. The “**6.012 pn Diode (pn diode)**” device is available in WebLab under the **Devices** menu. The details of the device connection are available on-line. Refer to Appendix A for basic information about the pn diode.

You have to do the following:

1) **(25 points)** Obtain I-V characteristics of the pn diode. Take measurements between -2 and 1 V. In the **measurement results panel** of WebLab, graph your results in the following way:

**Graph 1** Linear plot of I-V characteristics (V in x-axis in linear scale, I in y-axis in linear scale). Take a screen shot of this graph.

**Graph 2** Semilogarithmic plot of I-V characteristics (V in x-axis in linear scale, I in y-axis in logarithmic scale). Note: in a logarithmic scale, WebLab graphs the absolute of negative currents. Take a screen shot of this graph.

You might need to go back and forth a few times trying different measurement point distributions so that sufficient data is taken in all regions of interest. Think also about issues involved in sweeping voltage vs. sweeping current. The maximum current the HP4155B can support is 100mA ( $I_{\text{max}}=100\text{mA}$ ). The minimum current you can measure accurately is  $\approx 1\text{pA}$  ( $I_{\text{min}}\approx 1\text{pA}$ ) since the noise floor for the instrument is about 1pA.

2) **(20 points)** When you are happy with the results, download the data to your local machine and port them into your favorite spreadsheet program or MATLAB for graphing and analysis. Then do the following:

**Graph 3** Linear plot of I-V characteristics (V in x-axis in linear scale, I in y-axis in linear scale). Print out this graph.

**Graph 4** Semilogarithmic plot of I-V characteristics (V in x-axis in linear scale, I in y-axis in logarithmic scale). Note: in your spreadsheet program, you will have to compute

the absolute of the current before you can graph it in a logarithmic scale. Print out this graph.

3) (20 points) Study the ideal model for the I-V characteristics of the pn diode in Appendix A. Devise a simple scheme to extract from the measured data the saturation current,  $I_s$  (in A) and the temperature of the diode,  $T$  (in K). You can find the values of the fundamental constants that you need in Howe & Sodini. Illustrate your procedure graphically and give the extracted values. Remember if  $I_s < 1\text{pA}$  you cannot directly measure it when  $V$  is negative. You are just measuring the noise floor of the instrument.

4) (10 points) A more realistic model for a pn diode includes a parasitic series resistance, as discussed in Appendix A. Using the values of  $I_s$  and  $T$  derived in the previous section, devise a simple scheme to extract from the measured data the series resistance,  $R_s$  (in  $\Omega$ ), of the diode. Illustrate your procedure graphically and give the extracted value.

5) (25 points) Compare the experimental characteristics with those predicted by the theoretical models for the pn diode given in Appendix A. To do this, graph together the experimental measurements, the predictions of the ideal model, and the predictions of the model that includes series resistance. Plotting the I-V characteristics of the model that includes series resistance is a bit tricky because  $I$  is on both sides of the equation. A good way to do it is to solve for  $V$ , then compute  $V$  vs.  $I$ , and finally plot  $I$  vs.  $V$ .

Turn in the following graphs:

*Graph 5)* Linear plot of I-V characteristics ( $V$  in x-axis in linear scale,  $I$  in y-axis in linear scale). Show experimental data points with symbols, ideal model with dashed line and second-order model with continuous line. Print out this graph.

*Graph 6)* Semilogarithmic plot of I-V characteristics ( $V$  in x-axis in linear scale,  $I$  in y-axis in logarithmic scale). Show experimental data points with symbols, ideal model with dashed line and second-order model with continuous line. Print out this graph.

### **Additional information and assorted advice**

•The required graphs need not be too fancy, just simply correct. They must have proper tickmarks, axis labelling, and correct units. When there are several lines, each one should be properly identified (handwriting is OK).